

900V N-Channel Enhancement Mode MOSFET

Description

The AP4N90D/Y is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

General Features

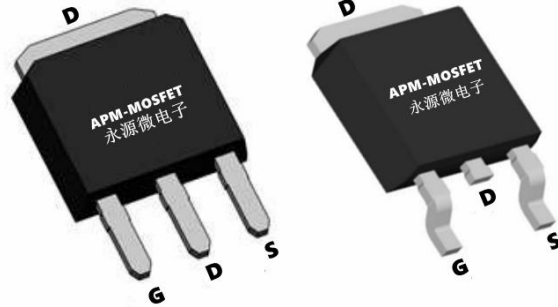
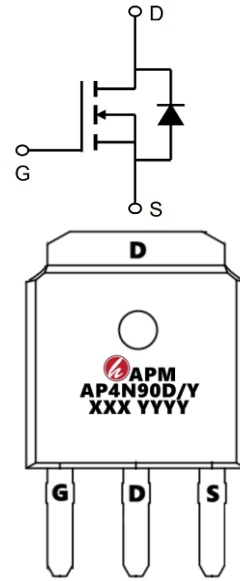
$V_{DS} = 900V$ $I_D = 4.0A$

$R_{DS(ON)} < 3500m\Omega$ @ $V_{GS}=10V$ (Type: 3000m Ω)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP4N90D	TO-252-3L	AP4N90D XXX YYYY	2500
AP4N90Y	TO-251S-3L	AP4N90Y XXX YYYY	4000

Absolute Maximum Ratings ($T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Units
V_{DSS}	Drain-Source Voltage	900	V
V_{GS}	Gate-Source Voltage	± 30	V
$I_D@T_C=25^{\circ}C$	Drain Current, V_{GS} @ 10V	4.0	A
$I_D@T_C=100^{\circ}C$	Drain Current, V_{GS} @ 10V	2.1	A
I_{DM}	Drain Current - Pulsed	16	A
E_{AS}	Single Pulsed Avalanche Energy	125	mJ
I_{AS}	Avalanche Current	6	A
E_{AR}	Repetitive Avalanche Energy	0.72	mJ
P_D	Power Dissipation	25	W
T_j, T_{stg}	Operating and Storage Temperature Range	-55 to +150	$^{\circ}C$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	5.0	$^{\circ}C/W$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	$^{\circ}C/W$

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	900	1000		V
ΔBV _{DSS} /ΔT _J	Breakdown Voltage Temperature Coefficient	I _D =250μA, Referenced to 25°C		0.74		V/°C
IDSS	Zero Gate Voltage Drain Current	V _{DS} =900V, V _{GS} =0V			1	μA
IDSS	Zero Gate Voltage Drain Current	V _{DS} =720V, TC=125°C			10	μA
IGSSF	Gate-Body Leakage Current, Forward	V _{GS} =30V, V _{DS} =0V			100	nA
IGSSR	Gate-Body Leakage Current, Reverse	V _{GS} =-30V, V _{DS} =0V			-100	nA
VGS(TH)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250 μA	2.0	3.0	4.5	V
RDS(On)	Drain-Source On-state Resistance	V _{GS} =10V, I _D =2.0A,		3000	3500	mΩ
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0V f=1.0MHz		674		pF
C _{oss}	Output Capacitance			71		pF
C _{rss}	Reverse Transfer Capacitance			13		pF
td(on)	Turn On Delay Time	V _{DD} =720V, I _D =4A, R _G =25Ω		37		ns
t _r	Rising Time			15		ns
td(off)	Turn Off Delay Time			144		ns
t _f	Fall Time			36		ns
Q _g	Total Gate Charge	V _{DS} =450V, I _D =4A, V _{GS} =10V		27		nC
Q _{gs}	Gate-Source Charge			3.5		nC
Q _{gd}	Gate-Drain Charge			14		nC
ISM	Maximum Pulsed Drain-Source Diode Forward Current				4	A
V _{SD}	Diode Forward Voltage	V _{GS} =0V, I _S =2A			1.4	V
trr	Reverse Recovery Time	V _{GS} =0V, I _S =4A, dI _F /dt=100 A/μs		1018		ns
Q _{rr}	Reverse Recovery Charge	Note4)		2.2		μC

Note :

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The EAS data shows Max. rating . L=10mH IAS=6A, VDD=50V, RG=25Ω, Starting T_J=25 °C
- 3、 The test condition is Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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Typical Characteristics

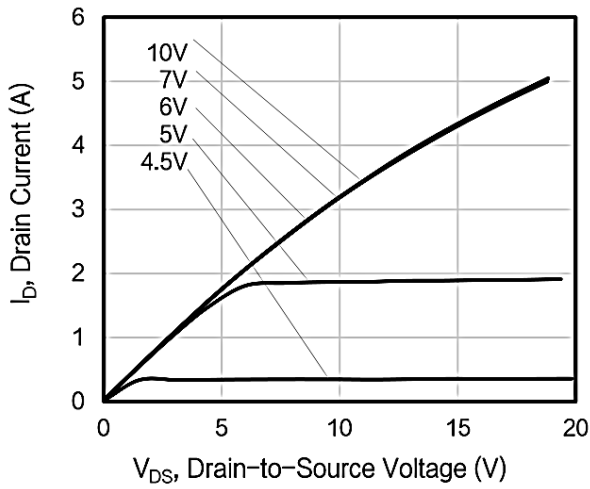


Figure 1. Output Characteristics

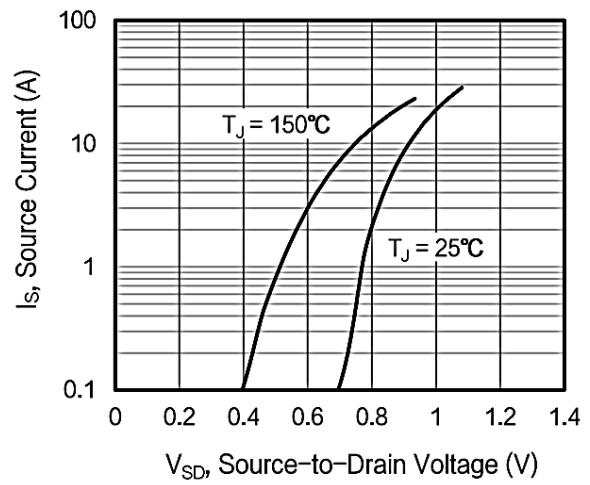


Figure 2. Body Diode Forward Voltage

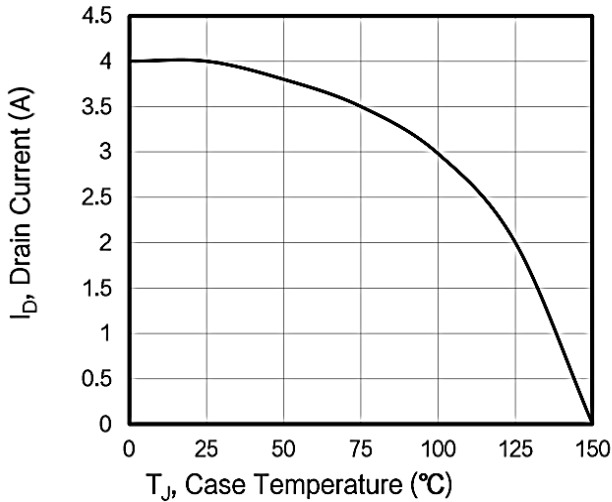


Figure3. Drain Current vs. Temperature

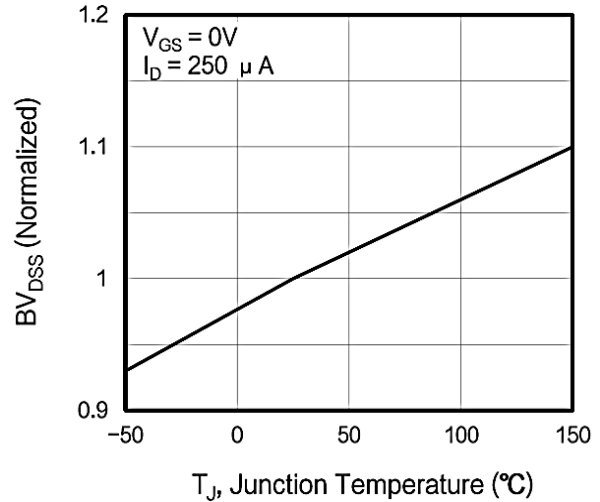


Figure4. BV_{DSS} Variation vs. Temperature

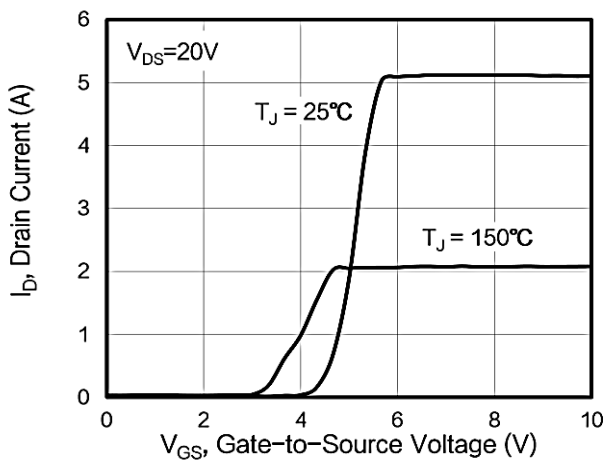


Figure 5. Transfer Characteristics

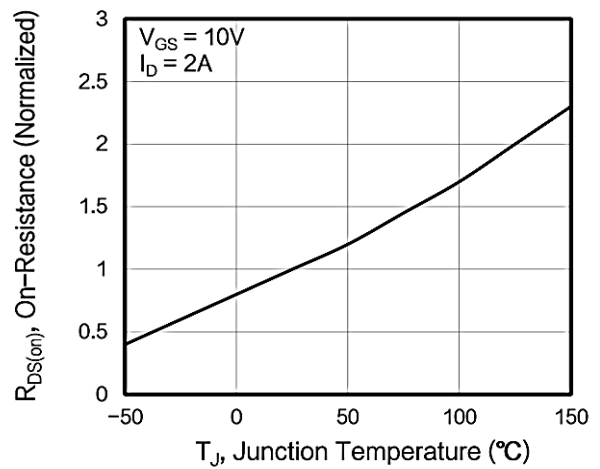


Figure 6. On-Resistance vs. Temperature

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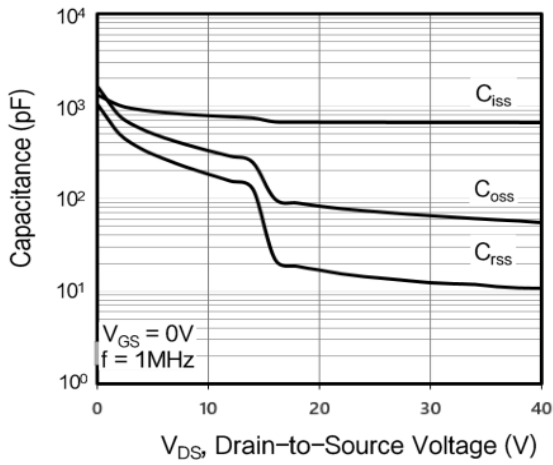


Figure 7. Capacitance

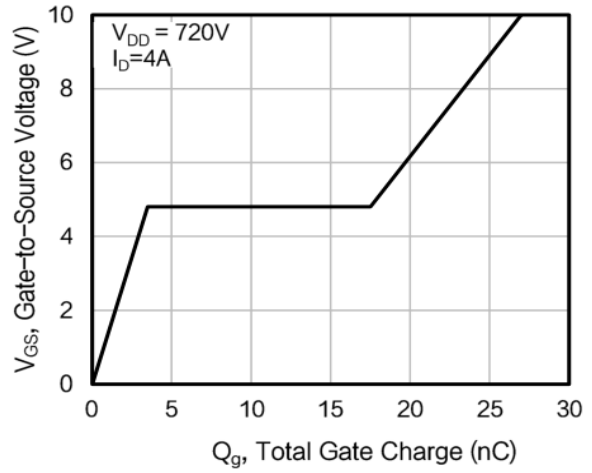


Figure 8. Gate Charge

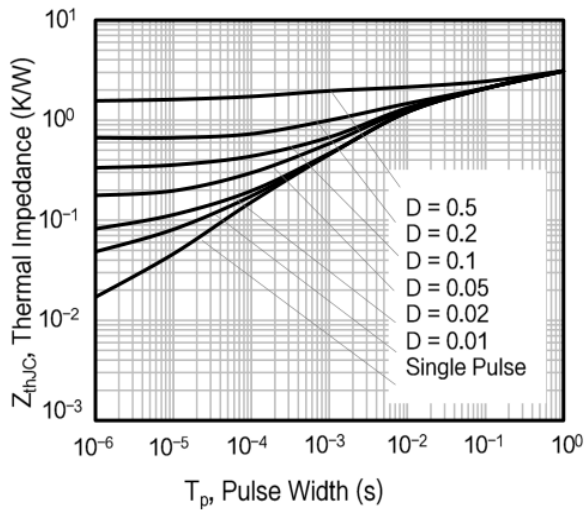
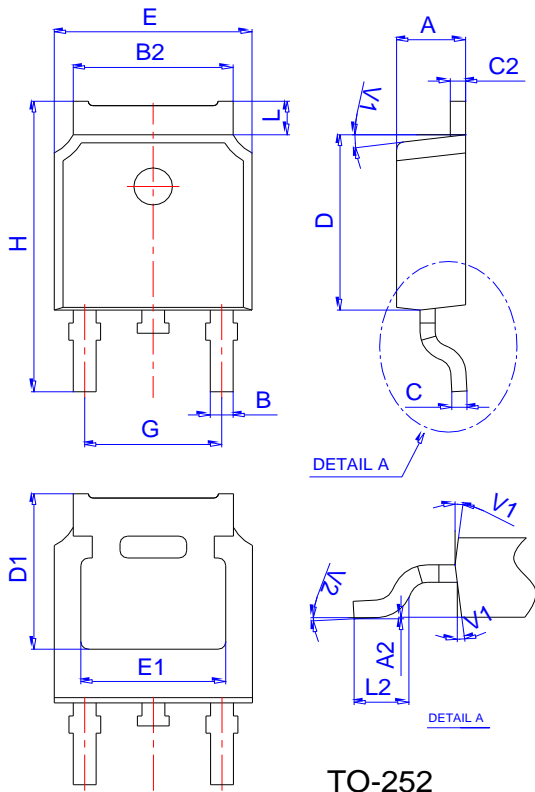


Figure 9. Transient Thermal Impedance

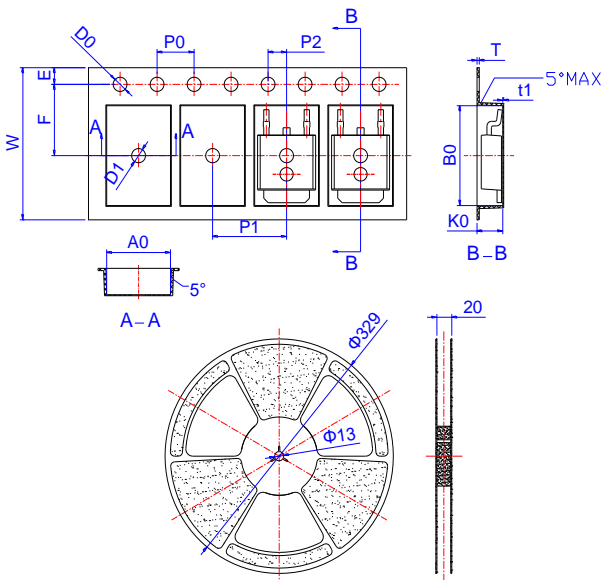
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Package Mechanical Data:TO-252-3L



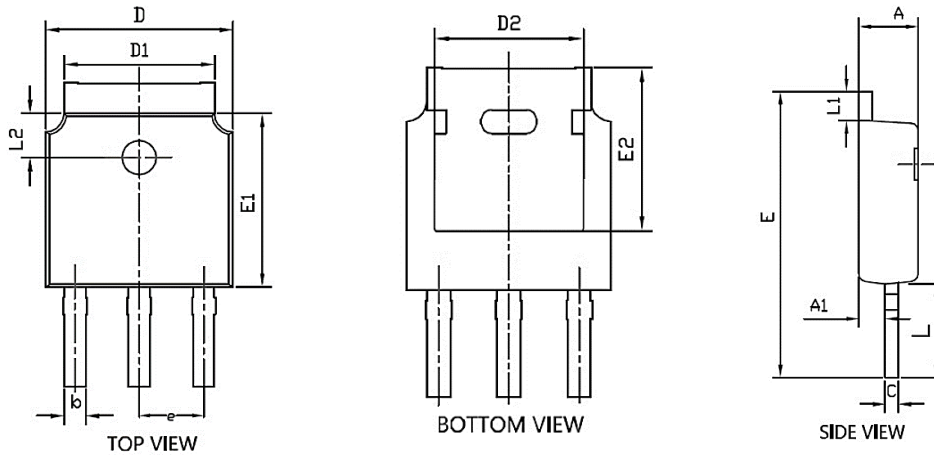
Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

Package Mechanical Data-TO-251S-3L



Symbol	Common		
	mm		
	Mim	Nom	Max
A	2.2	2.3	2.4
A1	0.9	1.0	1.1
b	0.66	0.76	0.86
C	0.46	0.52	0.58
D	6.50	6.6	6.7
D1	5.15	5.3	5.45
D2	4.6	4.8	4.95
E	10.4	----	11.5
E1	6.0	6.1	6.2
E2	5.400REF		
e	2.286BSC		
L	3.5	4.0	4.3
L1	0.9	---	1.27
L2	1.4	---	1.9

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Edition	Date	Change
REV1.0	2023/1/31	Initial release

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